Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/781,115	CRANDALL ET AL.	
Examiner	Art Unit	
Anthony Weier	1761	

SEARCHED						
	SEARCHED					
Class	Subclass	Date	Examiner			
426	634, 658, 577, 431	9/16/2005	AW			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Inventor Search	9/14/2005	AW	